

PACKAGE/ORDERING INFORMATION

MODEL	PACKAGE DESCRIPTION	SPECIFIED TEMPERATURE RANGE	ORDERING NUMBER	PACKAGE MARKING	PACKING OPTION
SGM7222	MSOP-10	-40°C to +85°C	SGM7222YMS10/TR	SGM7222 YMS10 XXXXX	Tape and Reel, 3000
	TQFN-1.8×1.4-10L	-40°C to +85°C	SGM7222YWQ10/TR	7222	Tape and Reel, 3000
	UTQFN-1.8×1.4-10L	-40°C to +85°C	SGM7222YUWQ10/TR	CAA XXX	Tape and Reel, 3000

MARKING INFORMATION

NOTE: XXX = Date Code and Trace Code. XXXXX = Date Code and Vendor Code.

MSOP-10

XXXXX

Vendor Code
Date Code - Week
Date Code - Year

UTQFN-1.8×1.4-10L

YYY
XXX

Serial Number

Trace Code

Date Code - Year

Green (RoHS & HSF): SG Micro Corp defines "Green" to mean Pb-Free (RoHS compatible) and free of halogen substances. If you have additional comments or questions, please contact your SGMICRO representative directly.

ABSOLUTE MAXIMUM RATINGS

V₊ to GND0V to 4.6V
 Analog, Digital Voltage Range -0.3V to (V₊) + 0.3V
 Continuous Current HSDn or Dn ±100mA
 Peak Current HSDn or Dn ±150mA
 Junction Temperature +150°C
 Storage Temperature Range -65°C to +150°C
 Lead Temperature (Soldering, 10s) +260°C
 ESD Susceptibility
 HBM 8000V
 MM 400V

RECOMMENDED OPERATING CONDITIONS

Operating Temperature Range -40°C to +85°C

OVERSTRESS CAUTION

Stresses beyond those listed in Absolute Maximum Ratings may cause permanent damage to the device. Exposure to absolute maximum rating conditions for extended periods may affect reliability. Functional operation of the device at any conditions beyond those indicated in the Recommended Operating Conditions section is not implied.

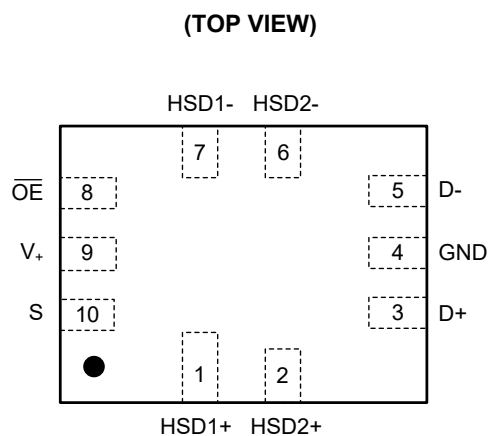
ESD SENSITIVITY CAUTION

This integrated circuit can be damaged by ESD if you don't pay attention to ESD protection. SGMICRO recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage. ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

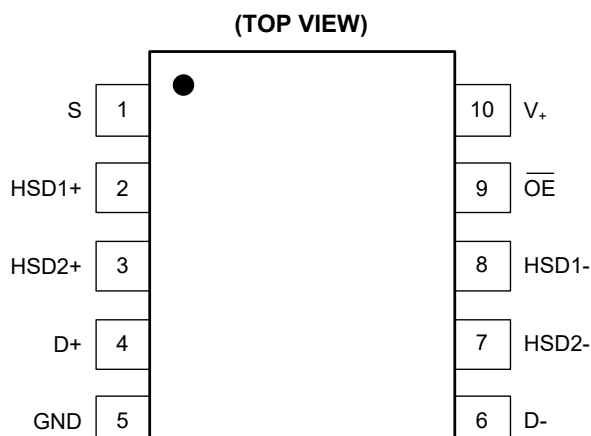
DISCLAIMER

SG Micro Corp reserves the right to make any change in circuit design, or specifications without prior notice.

PIN CONFIGURATIONS



TQFN-1.8×1.4-10L/UTQFN-1.8×1.4-10L



MSOP-10

PIN DESCRIPTION

PIN		NAME	FUNCTION
TQFN-1.8×1.4-10L/ UTQFN-1.8×1.4-10L	MSOP-10		
1, 2	2, 3	HSD1+, HSD2+	Data Ports.
3, 5	4, 6	D+, D-	
7, 6	8, 7	HSD1-, HSD2-	
4	5	GND	Ground.
8	9	$\overline{\text{OE}}$	Output Enable.
9	10	V+	Power Supply.
10	1	S	Select Input.

FUNCTION TABLE

$\overline{\text{OE}}$	S	HSD1+ HSD1-	HSD2+ HSD2-
0	0	ON	OFF
0	1	OFF	ON
1	x	OFF	OFF

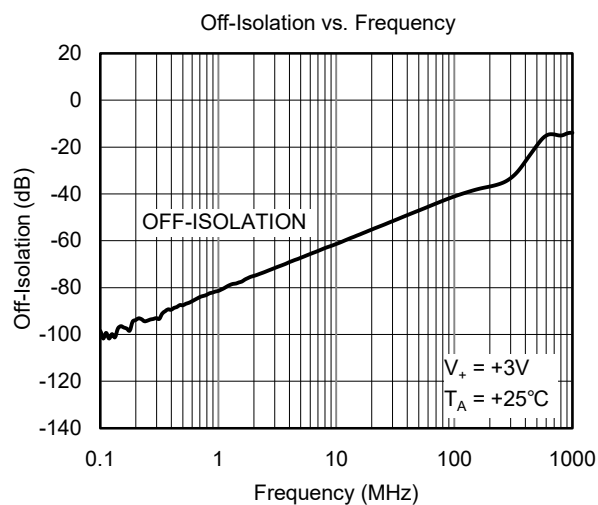
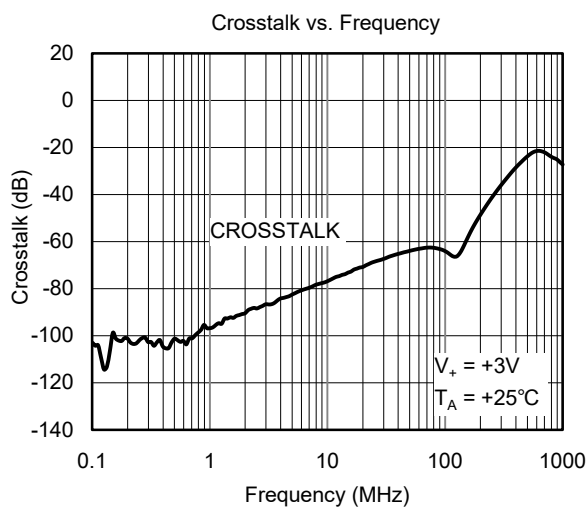
NOTE: Switches shown for logic "0" input.

ELECTRICAL CHARACTERISTICS

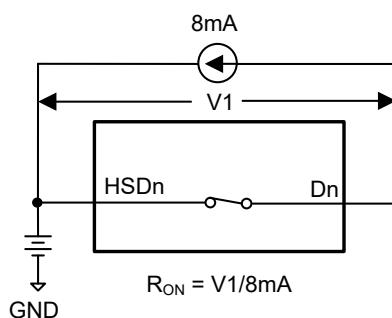
($V_+ = 1.8\text{V}$ to 4.3V , $\text{GND} = 0\text{V}$, $V_{\text{IH}} = 1.6\text{V}$, $V_{\text{IL}} = 0.5\text{V}$, Full = -40°C to $+85^\circ\text{C}$. Typical values are at $V_+ = 3.3\text{V}$, $T_A = +25^\circ\text{C}$, unless otherwise noted.)

PARAMETER	SYMBOL	CONDITIONS	TEMP	MIN	TYP	MAX	UNITS
Analog Switch							
Analog I/O Voltage (HSD1+, HSD1-, HSD2+, HSD2-)	V_{IS}		Full	0		V_+	V
On-Resistance	R_{ON}	$V_+ = 3\text{V}$, $V_{\text{IS}} = 0\text{V}$ to 0.4V , $I_{\text{D}} = 8\text{mA}$, Test Circuit 1	$+25^\circ\text{C}$		4.5	8.5	Ω
			Full			9	
On-Resistance Match Between Channels	ΔR_{ON}	$V_+ = 3\text{V}$, $V_{\text{IS}} = 0\text{V}$ to 0.4V , $I_{\text{D}} = 8\text{mA}$, Test Circuit 1	$+25^\circ\text{C}$		0.15	0.6	Ω
			Full			1.6	
On-Resistance Flatness	$R_{\text{FLAT(ON)}}$	$V_+ = 3\text{V}$, $V_{\text{IS}} = 0\text{V}$ to 1V , $I_{\text{D}} = 8\text{mA}$, Test Circuit 1	$+25^\circ\text{C}$		1.5	2.0	Ω
			Full			2.6	
Power Off Leakage Current (D+, D-)	I_{OFF}	$V_+ = 0\text{V}$, $V_{\text{D}} = 0\text{V}$ to 3.6V , V_{S} , $V_{\text{OE}} = 0\text{V}$ or 3.6V	Full			1	μA
Increase in I_+ per Control Voltage	I_{CCT}	$V_+ = 3.6\text{V}$, V_{S} or $V_{\text{OE}} = 2.6\text{V}$	Full			5	μA
Source Off Leakage Current	$I_{\text{HSD2(OFF)}}$, $I_{\text{HSD1(OFF)}}$	$V_+ = 3.6\text{V}$, $V_{\text{IS}} = 3.3\text{V}/0.3\text{V}$, $V_{\text{D}} = 0.3\text{V}/3.3\text{V}$	Full			1	μA
Channel On Leakage Current	$I_{\text{HSD2(ON)}}$, $I_{\text{HSD1(ON)}}$	$V_+ = 3.6\text{V}$, $V_{\text{IS}} = 3.3\text{V}/0.3\text{V}$, $V_{\text{D}} = 3.3\text{V}/0.3\text{V}$ or floating	Full			1	μA
Digital Inputs							
Input High Voltage	V_{IH}		Full	1.6			V
Input Low Voltage	V_{IL}		Full			0.5	V
Input Leakage Current	I_{IN}	$V_+ = 3\text{V}$, V_{S} , $V_{\text{OE}} = 0\text{V}$ or V_+	Full			1	μA
Dynamic Characteristics							
Turn-On Time	t_{ON}	$V_{\text{IS}} = 0.8\text{V}$, $R_{\text{L}} = 50\Omega$, $C_{\text{L}} = 10\text{pF}$, Test Circuit 2	$+25^\circ\text{C}$		10		ns
Turn-Off Time	t_{OFF}		$+25^\circ\text{C}$		22		ns
Break-Before-Make Time Delay	t_{D}	$V_{\text{IS}} = 0.8\text{V}$, $R_{\text{L}} = 50\Omega$, $C_{\text{L}} = 10\text{pF}$, Test Circuit 3	$+25^\circ\text{C}$		4		ns
Propagation Delay	t_{PD}	$R_{\text{L}} = 50\Omega$, $C_{\text{L}} = 10\text{pF}$	$+25^\circ\text{C}$		0.3		ns
Off Isolation	O_{ISO}	Signal = 0dBm , $R_{\text{L}} = 50\Omega$, $f = 250\text{MHz}$, Test Circuit 4	$+25^\circ\text{C}$		-35		dB
Channel-to-Channel Crosstalk	X_{TALK}	Signal = 0dBm , $R_{\text{L}} = 50\Omega$, $f = 250\text{MHz}$, Test Circuit 5	$+25^\circ\text{C}$		-41		dB
-3dB Bandwidth	BW	Signal = 0dBm , $R_{\text{L}} = 50\Omega$, $C_{\text{L}} = 5\text{pF}$, Test Circuit 6	$+25^\circ\text{C}$		550		MHz
Channel-to-Channel Skew	t_{SKEW}	$R_{\text{L}} = 50\Omega$, $C_{\text{L}} = 10\text{pF}$	$+25^\circ\text{C}$		0.05		ns
Charge Injection Select Input to Common I/O	Q	$V_{\text{G}} = \text{GND}$, $C_{\text{L}} = 1\text{nF}$, $R_{\text{G}} = 0\Omega$, $Q = C_{\text{L}} \times V_{\text{OUT}}$, Test Circuit 7	$+25^\circ\text{C}$		11		pC
HSD+, HSD-, D+, D- On Capacitance	C_{ON}		$+25^\circ\text{C}$		6.5		pF
Power Requirements							
Power Supply Range	V_+		Full	1.8		4.3	V
Power Supply Current	I_+	$V_+ = 3\text{V}$, V_{S} , $V_{\text{OE}} = 0\text{V}$ or V_+	Full			1	μA

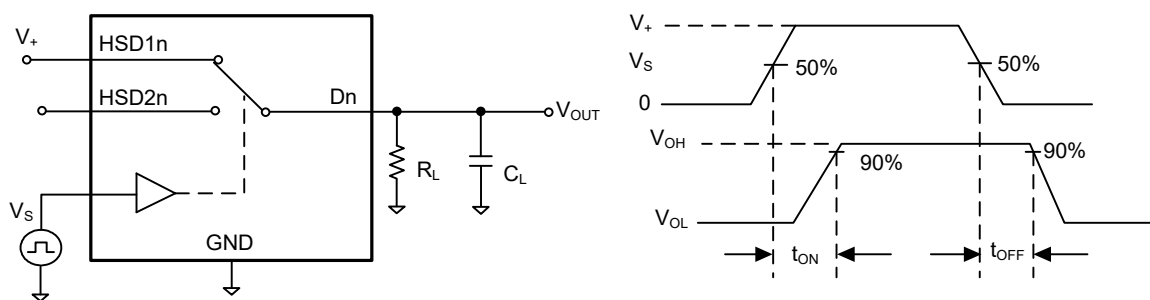
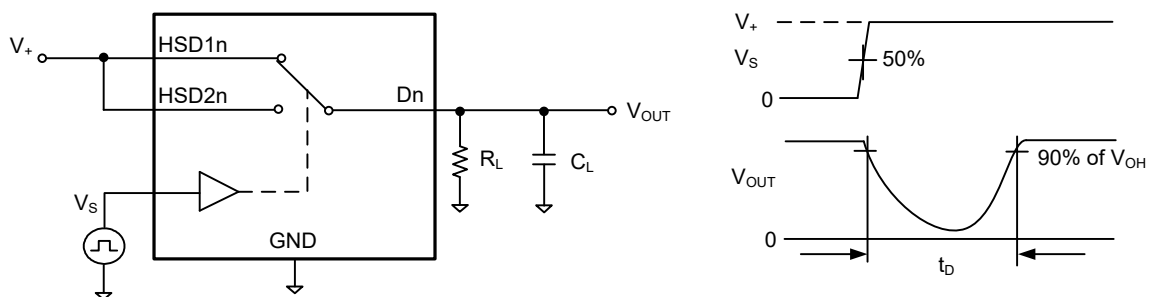
TYPICAL PERFORMANCE CHARACTERISTICS



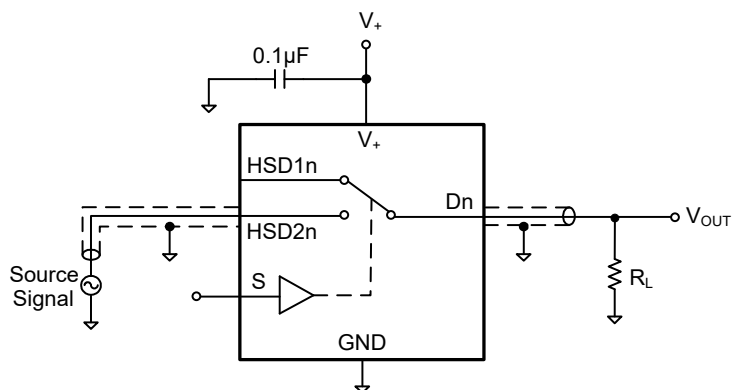
TEST CIRCUITS



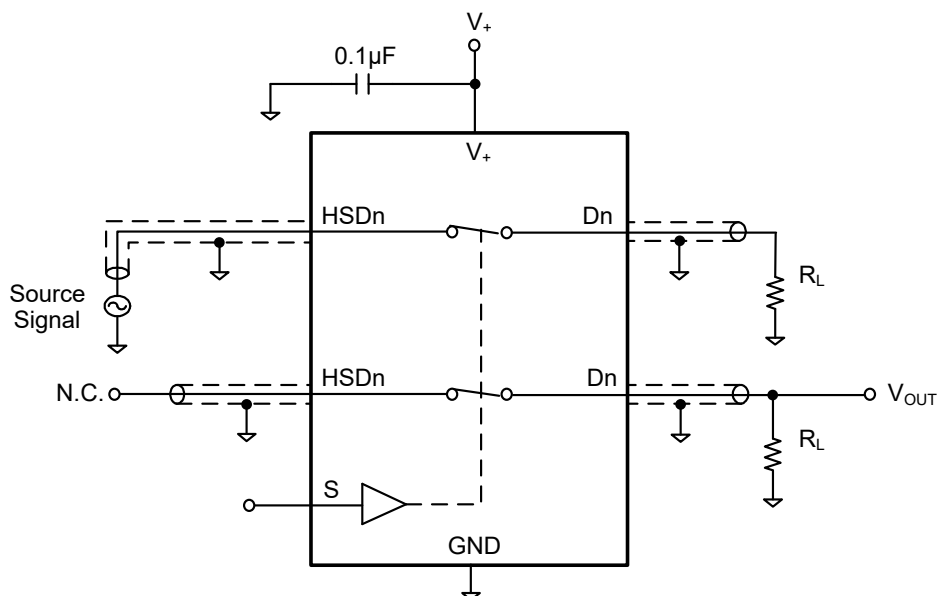
Test Circuit 1. On-Resistance

Test Circuit 2. Switching Times (t_{ON}, t_{OFF})Test Circuit 3. Break-Before-Make Time (t_d)

TEST CIRCUITS (continued)



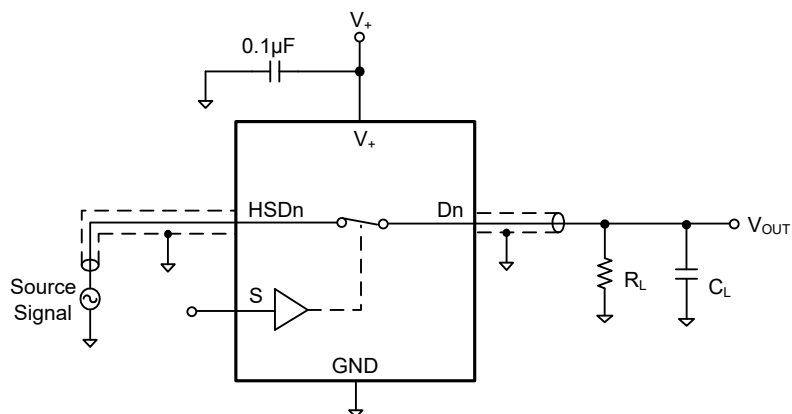
Test Circuit 4. Off Isolation



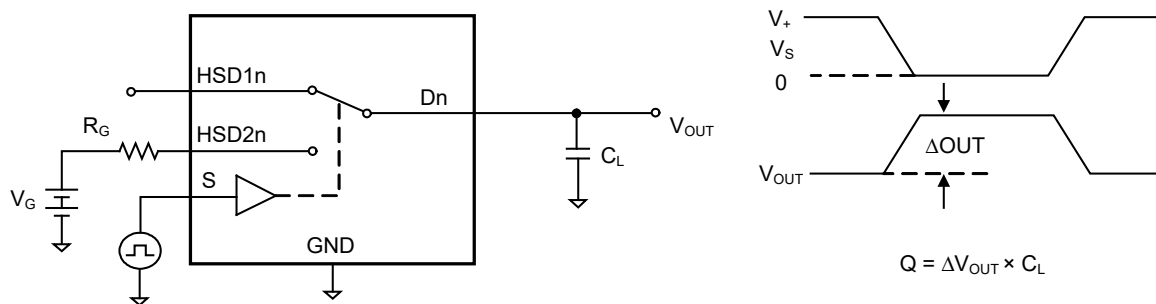
$$\text{Channel To Channel Crosstalk} = -20 \times \log \frac{V_{\text{HSDn}}}{V_{\text{OUT}}}$$

Test Circuit 5. Channel-to-Channel Crosstalk

TEST CIRCUITS (continued)



Test Circuit 6. -3dB Bandwidth



Test Circuit 7. Charge Injection (Q)

APPLICATION NOTES

Meeting USB 2.0 V_{BUS} Short Requirements

In section 7.1.1 of the USB 2.0 specification, it notes that USB devices must be able to withstand a V_{BUS} short to D+ or D- when the USB device is either powered off or powered on. The SGM7222 can be successfully configured to meet both these requirements.

Power-Off Protection

For a V_{BUS} short circuit the switch is expected to withstand such a condition for at least 24 hours. The SGM7222 has specially designed circuitry which prevents unintended signal bleed through as well as guaranteed system reliability during a power-down,

over-voltage condition. The protection has been added to the common pins (D+, D-).

Power-On Protection

The USB 2.0 specification also notes that the USB device should be capable of withstanding a V_{BUS} short during transmission of data. This modification works by limiting current flow back into the V_+ rail during the over-voltage event so current remains within the safe operating range. In this application, the switch passes the full 5.25V input signal through to the selected output, while maintaining specified off isolation on the un-selected pins.

SGM7222 USB2.0 Signal Quality Compliance Tests

Figures 1 and 2 show the test results for USB eye diagram tests. A summary of the USB tests is provided in Table 1. The SGM7222 passes the high speed signal quality, eye diagram and jitter tests.

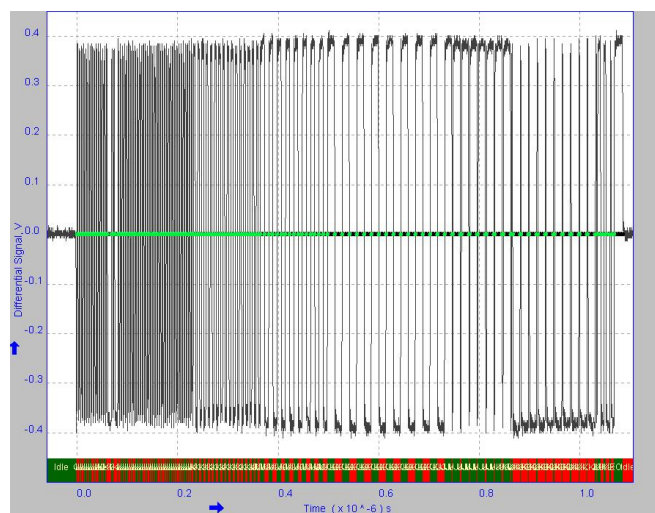
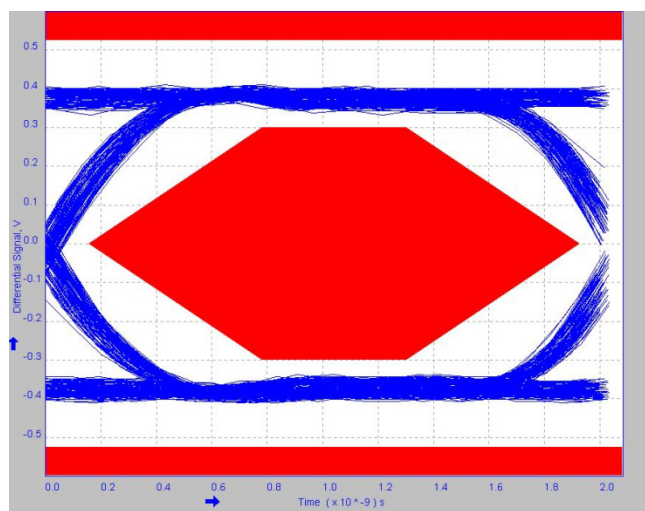


Figure 1. Waveform Plot

Figure 2. High Speed Signal Quality Eye Diagram Test
($V_+ = 3.3V$)

APPLICATION NOTES (continued)

Table 1. Summary of the USB 2.0 Signal Quality Tests Results

Measurement Name	MIN	MAX	Mean	pk-pk	Standard Deviation	RMS	Population	Status
Eye Diagram Test	-	-	-	-	-	-	-	Pass
Signal Rate	469.9358 Mbps	493.4413 Mbps	479.9700 Mbps	0.0000 bps	5.586580 Mbps	480.4200 Mbps	512	Pass
EOP Width	-	-	16.58804ns	-	-	-	1	Pass
EOP Width (Bits)	-	-	7.961762	-	-	-	1	Pass
Falling Edge Rate	1.064231 kV/ μ s	1.228955 kV/ μ s	1.143136 kV/ μ s	164.7235 V/ μ s	35.43800 V/ μ s	1.143680 kV/ μ s	107	Pass
Rising Edge Rate	1.063269 kV/ μ s	1.227966 kV/ μ s	1.136558 kV/ μ s	164.6970 V/ μ s	31.49494 V/ μ s	1.136990 kV/ μ s	108	Pass

Additional Information:

Consecutive Jitter range: -82.97ps to 72.87ps RMS Jitter 35.08ps

KJ Paired Jitter range: -25.05ps to 23.05ps RMS Jitter 9.259ps

JK Paired Jitter range: -20.96ps to 30.12ps RMS Jitter 9.734ps

- Rising Edge Rate: 1.136558kV/ μ s (Equivalent Rise Time = 563.10ps)
- Falling Edge Rate: 1.143136kV/ μ s (Equivalent Fall Time = 559.86ps)

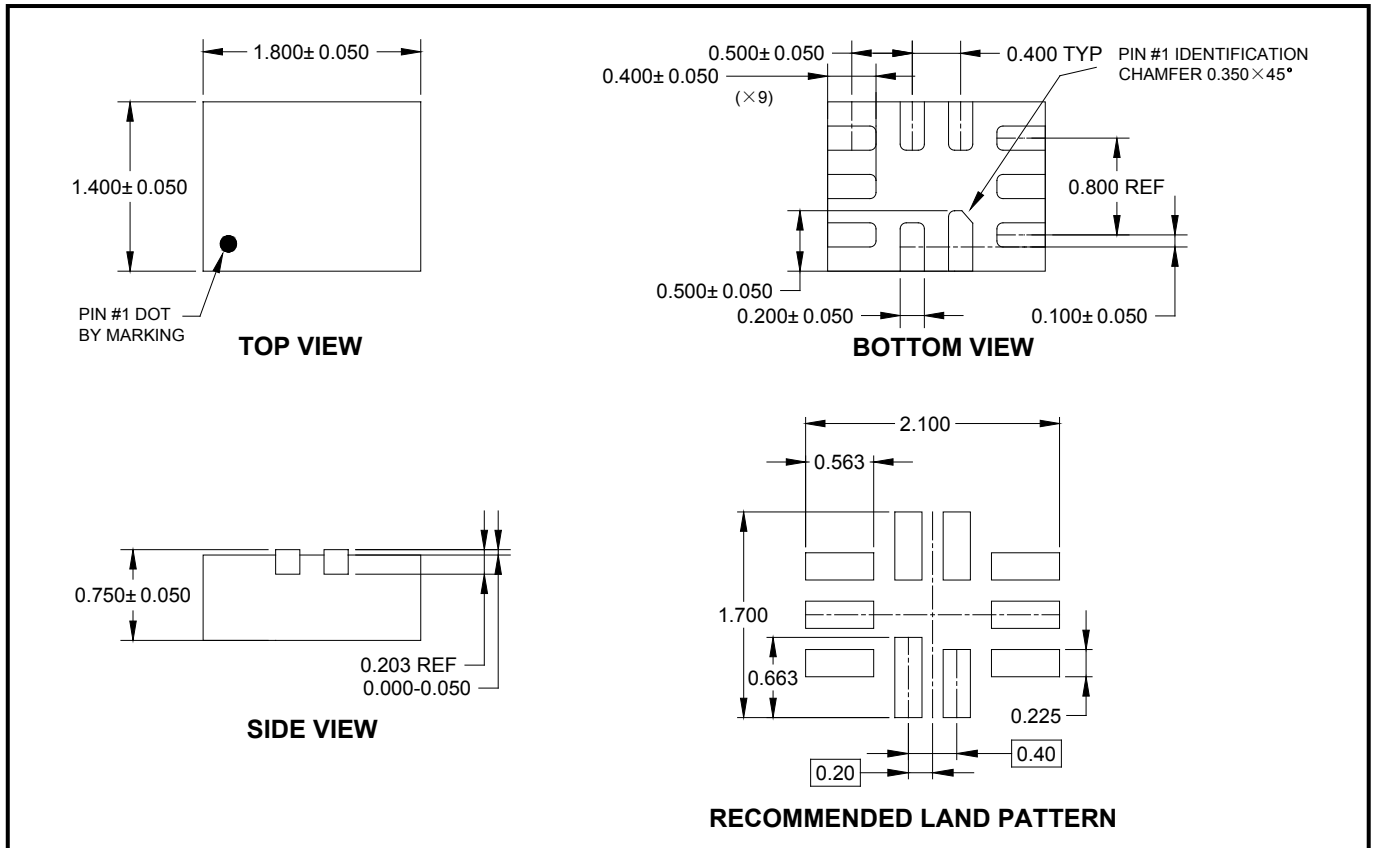
REVISION HISTORY

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

APRIL 2019 – REV.B.2 to REV.B.3	Page
Updated Package/Ordering Information section.....	2
MAY 2014 – REV.B.1 to REV.B.2	Page
Updated Absolute Maximum Ratings section.....	2
JANUARY 2013 – REV.B to REV.B.1	Page
Added Recommended Land Pattern section.....	12, 13, 14
Added Tape and Reel Information section.....	15, 16
MAY 2011 – REV.A.3 to REV.B	Page
Updated package option.....	All
MARCH 2011 – REV.A.2 to REV.A.3	Page
Updated Package Outline Dimensions section	12, 13, 14
FEBRUARY 2010 – REV.A.1 to REV.A.2	Page
Updated Test Circuits section	6, 8
SEPTEMBER 2009– REV.A to REV.A.1	Page
Added new package	All
Updated Absolute Maximum Ratings section.....	2
Changes from Original (DECEMBER 2008) to REV.A	Page
Changed from product preview to production data.....	All

PACKAGE OUTLINE DIMENSIONS

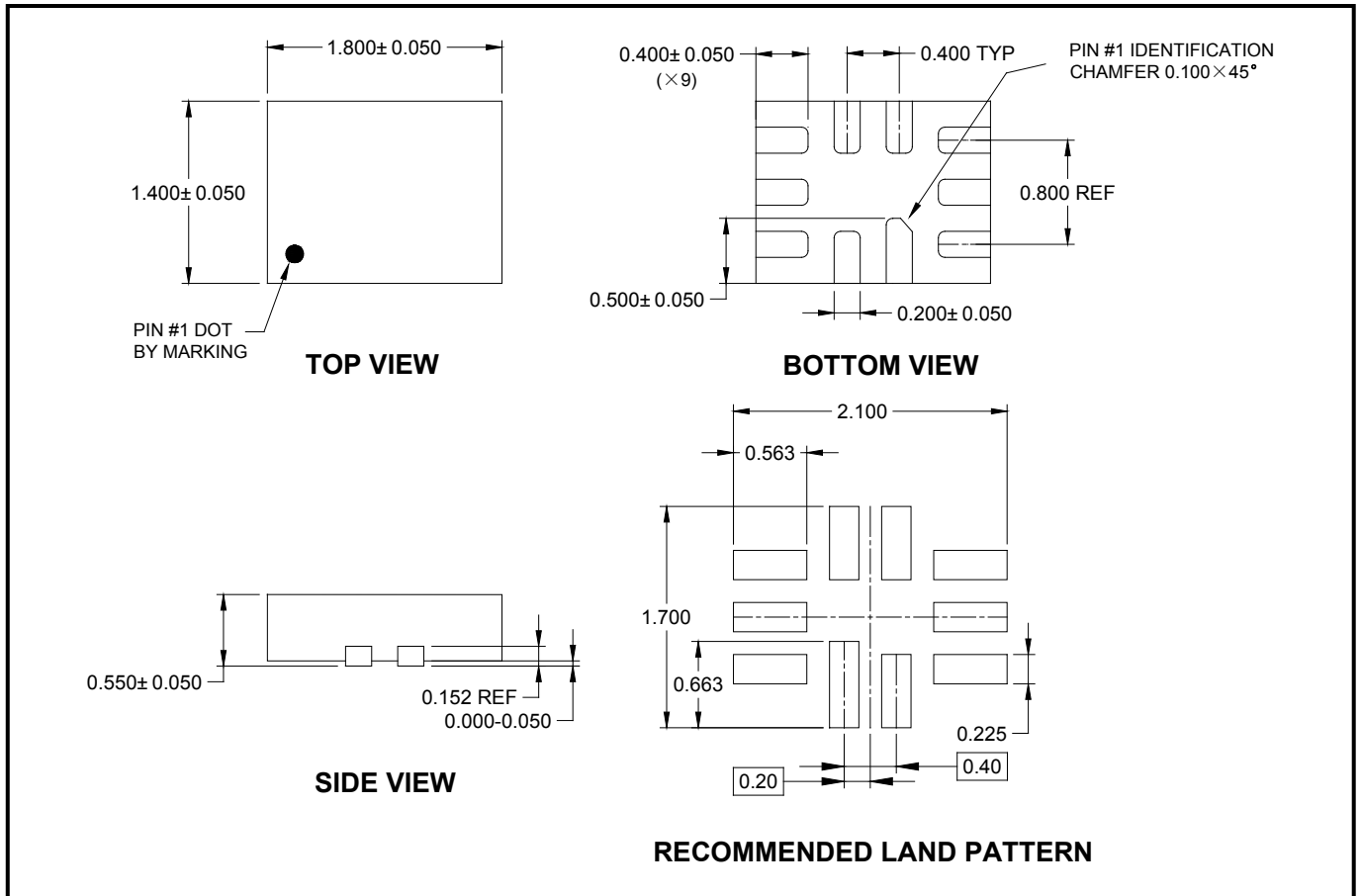
TQFN-1.8×1.4-10L



NOTE: All linear dimensions are in millimeters.

PACKAGE OUTLINE DIMENSIONS

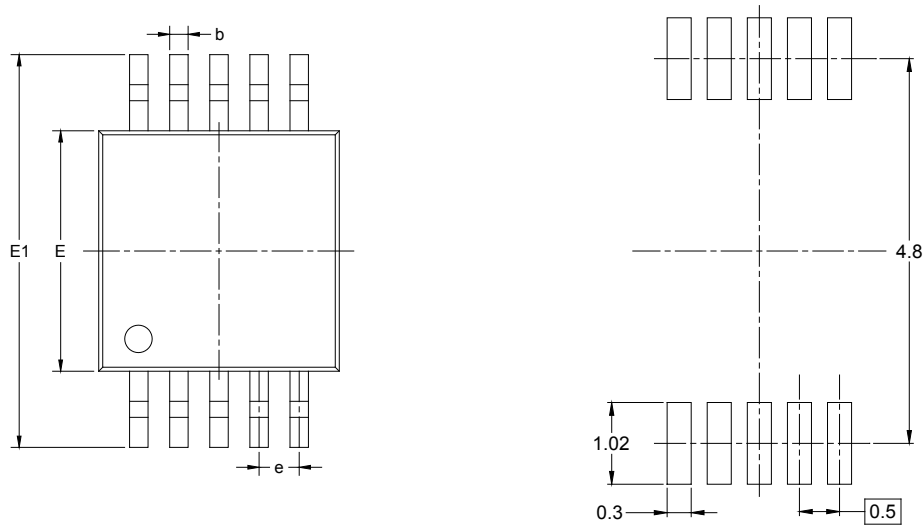
UTQFN-1.8×1.4-10L



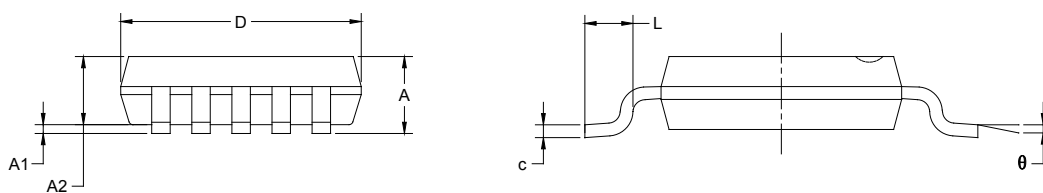
NOTE: All linear dimensions are in millimeters.

PACKAGE OUTLINE DIMENSIONS

MSOP-10



RECOMMENDED LAND PATTERN (Unit: mm)

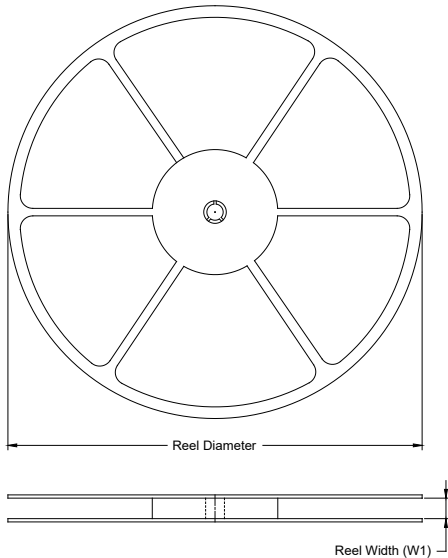


Symbol	Dimensions In Millimeters		Dimensions In Inches	
	MIN	MAX	MIN	MAX
A	0.820	1.100	0.032	0.043
A1	0.020	0.150	0.001	0.006
A2	0.750	0.950	0.030	0.037
b	0.180	0.280	0.007	0.011
c	0.090	0.230	0.004	0.009
D	2.900	3.100	0.114	0.122
E	2.900	3.100	0.114	0.122
E1	4.750	5.050	0.187	0.199
e	0.500 BSC		0.020 BSC	
L	0.400	0.800	0.016	0.031
θ	0°	6°	0°	6°

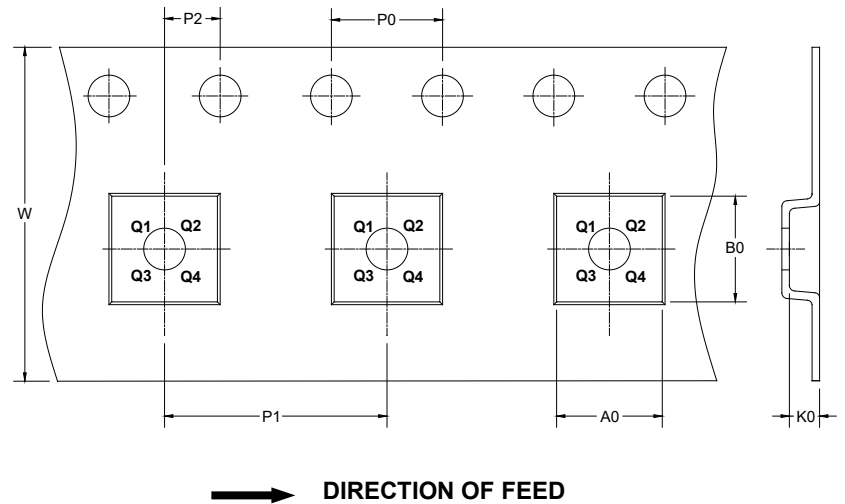
PACKAGE INFORMATION

TAPE AND REEL INFORMATION

REEL DIMENSIONS



TAPE DIMENSIONS



NOTE: The picture is only for reference. Please make the object as the standard.

KEY PARAMETER LIST OF TAPE AND REEL

Package Type	Reel Diameter	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P0 (mm)	P1 (mm)	P2 (mm)	W (mm)	Pin1 Quadrant
TQFN-1.8×1.4-10L	7"	9.0	1.75	2.10	1.00	4.0	4.0	2.0	8.0	Q1
UTQFN-1.8×1.4-10L	7"	9.0	1.75	2.10	0.70	4.0	4.0	2.0	8.0	Q1
MSOP-10	13"	12.4	5.20	3.30	1.20	4.0	8.0	2.0	12.0	Q1

DD0001

PACKAGE INFORMATION

CARTON BOX DIMENSIONS



NOTE: The picture is only for reference. Please make the object as the standard.

KEY PARAMETER LIST OF CARTON BOX

Reel Type	Length (mm)	Width (mm)	Height (mm)	Pizza/Carton
7" (Option)	368	227	224	8
7"	442	410	224	18
13"	386	280	370	5

DD0002